

Search Notes

Application/Control No.

10/777,026

Examiner

Binh X. Tran

Applicant(s)/Patent under
Reexamination

KAWAGUCHI ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
216	68	10/25/2006	BT
216	69	10/25/2006	BT
216	73	10/25/2006	BT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updates keywords search using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	10/25/2006	BT